In re Application	E UNIT	ED STATES PATENT AND	TRADEMARK OFFICE
In re Application	of)
Nikolay I. Agladze	e, Alber	t J. Sievers) Group Art Unit No. 2877
Application No.	:	10/720,763) Examiner:) Samuel A. Turner
Filed	:	November 25, 2003)
For	:	Miniaturized Holographic Fourier Transform Spectrometer with Digital Aberration Correction))))

INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to the provisions of 37 CFR 1.97 and 1.98, applicants hereby submit the documents listed on the attached PTO-1449A and PTO-1449B.

Copies of the cited publications are enclosed. Copies of the cited patents have not been included, but will be furnished upon request.

Respectfully submitted,

Nikolay I. Agladze, Albert J. Sievers Applicant JONES, TULLAR & COOPER, P.C. Attorneys for Applicant

Seorge M. Cooper Reg No. 20,201

July 21, 2004 JONES, TULLAR & COOPER, P.C. P.O. Box 2266 Eads Station Arlington, Virginia 22202 (703) 415-1500 Attorney Docket: 10/720,763

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PTO/SB/08A (10-96)
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Substitute for form 1449A/PTO

Sheet

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

of

Complete if Known					
Application Number	10/720,763				
Filing Date	Even Date Herewith				
First Named Inventor	Nikolay I. Agladze				
Group Art Unit	2877				
Examiner Name	Samuel A. Turner				
Attorney Docket Number	CRF D-3094/US				

E /				U.S. PATENT DOCUI	MENTS	
Examiner Initials	Cite No.1	U.S. Patent Document Kind Code ² (if known)		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		6,721,057		Reininger	04-13-2004	
		6,687,007		Meigs	02-03-2004	
		6,075,599		Milman et al.	06-13-2000*	
		6,051,835	Ī	Pettipiece et al.	04-18-2000	
		5,781,293		Padgett et al.	07-14-1998	,
		4,976,542		Smith	12-11-1990	
		4,585,345		Inoue	04-29-1986	
	*					
				*Subject to terminal		
				disclaimer		
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	FOREIGN PATENT DOCUMENTS										
Examiner	Cite	Foreign Patent Document		Name of Patentee or	Date of Publication of	Pages, Columns, Lines, Where Relevant					
Initials	No.1	Office ³	Number ⁴	Kind Code ⁵ (<i>if known</i>)	Applicant of Cited Document	Cited Document MM-DD-YYYY Passages or Relevant Figures Appear		Le			
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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Substitute fo	or form 1449B/PTO			Complete if Known				
				Application Number	10/720,763	70,, 5		
INFO	RMATION D	ISCLO	SURE	Filing Date	Even Date Herewith			
STAT	EMENT BY	APPLI	CANT	First Named Inventor	Nikolay I. Agladze	JUL 2 1 200		
				Art Unit	2877	P. C.		
	(Use as many sheets a	s necessary)		Examiner Name	Samuel A. Turner	& TRADEMA		
Sheet	1	of	1	Attorney Docket Number	CRF D-3094/US			

	NON PATENT LITERATURE DOCUMENTS							
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	-2					
	1	"Digital array scanned interferometer: sensors and results," Wm Hayden Smith and Philip D. Hammer; Applied Optics, Vol. 35, No. 16, luJune 1996						
·	2	"Photographic Method of Recording in Fourier Spectrometry," I.P. Petrov and B.N. Grechushnikov; Optics and Spectroscopy, 19, p. 82-83 (1965)						
	3	"Computational Aberration Correction for an Arbitrary Linear Imaging System," L. J. Allen, M. P. Oxley, and D. Paganin; Physical Review Letters, Vol. 87, No. 12, 17 September 2001						
	4	"Effects of abberations on spatially modulated Föurier transform spectrometers," R. Glenn Sellar, J. Bruce Rafert; Optical Engineering, September 1994, Vol. 33, No. 9/3087						
	5	"Fourier transform spectrometer with a self-scanning photodiode array," Takayuki Okamoto, Satoshi Kawata, and Shigeo Minami; Applied Optics, 15 January 1984, Vol. 23, No. 2						
	6	"Spatially Encoded Fourier Transform Spectroscopy in the Ultraviolet to Near-Infrared," Jonathan V. Sweedler and M. Bonner Denton; Applied Spectroscopy, Vol. 43, No. 8, 1989						
	7	"Monolithic Fourier-transform imaging spectrometer," J. Bruce Rafert, R. Glenn Sellar, and Joel H. Blatt; Applied Optics, Vol. 34, No. 31, 1 November 1995						
	8	"Phase Retrieval through Focus Variation for Ultra-Resolution in Field-Emission Transmission Electron Microscopy," Wim Coene and Guido Janssen, Marc Op de Beeck and Dirk Van Dyck; Physical Review						
		Letters, Vol. 69, No. 26, 28 December 1992						
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Examiner	Date	
Signature	Considered	

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